



EECS 150 Fall 2003

Lab Lecture 5

Debugging

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Today

- Debugging Techniques
- Simulation vs Hardware Debugging
- The Debugging Lab
- ChipScope Overview



Techniques

- PartI: Bottom-up Testing
- PartII: Designing Test Hardware
- PartIII: Testing of FSMs
- PartIV: Probing Internal Signals



Simulation vs. Hardware Debug

- Debugging in Simulation:
 - Slow run time
 - Fast debug time (waveform, text)
 - Very high coverage (90-100%)
 - Easy to fix!
- Debugging in Hardware:
 - Fast run time
 - Slow debug time
 - No or little internal visibility
 - It might be too late to fix (ASICs)



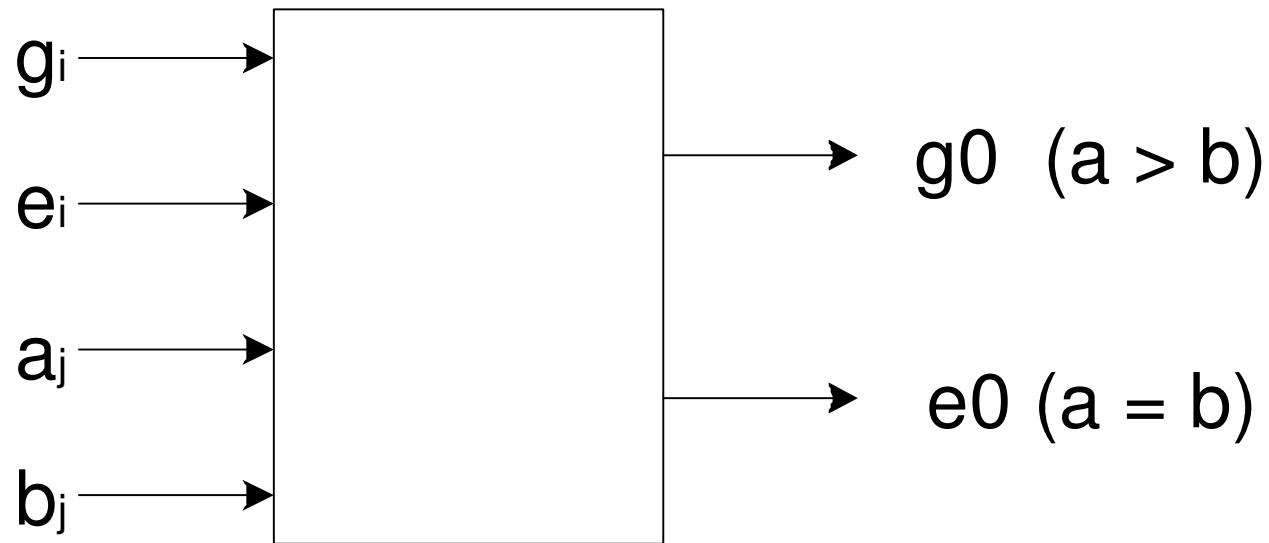
Test Case Generation

- Complete Coverage: Exhaustive Testing
- FSM: Test all Transitions and States
- In practice: Goal is to get 95%+ Coverage
- Correct by Design: Only the Coverage Specified by Design



Part I: Bottom Level Testing (1)

one_bit_comp



What does it mean if $(g_0 == 0)$ and $(e_0 == 0)$?

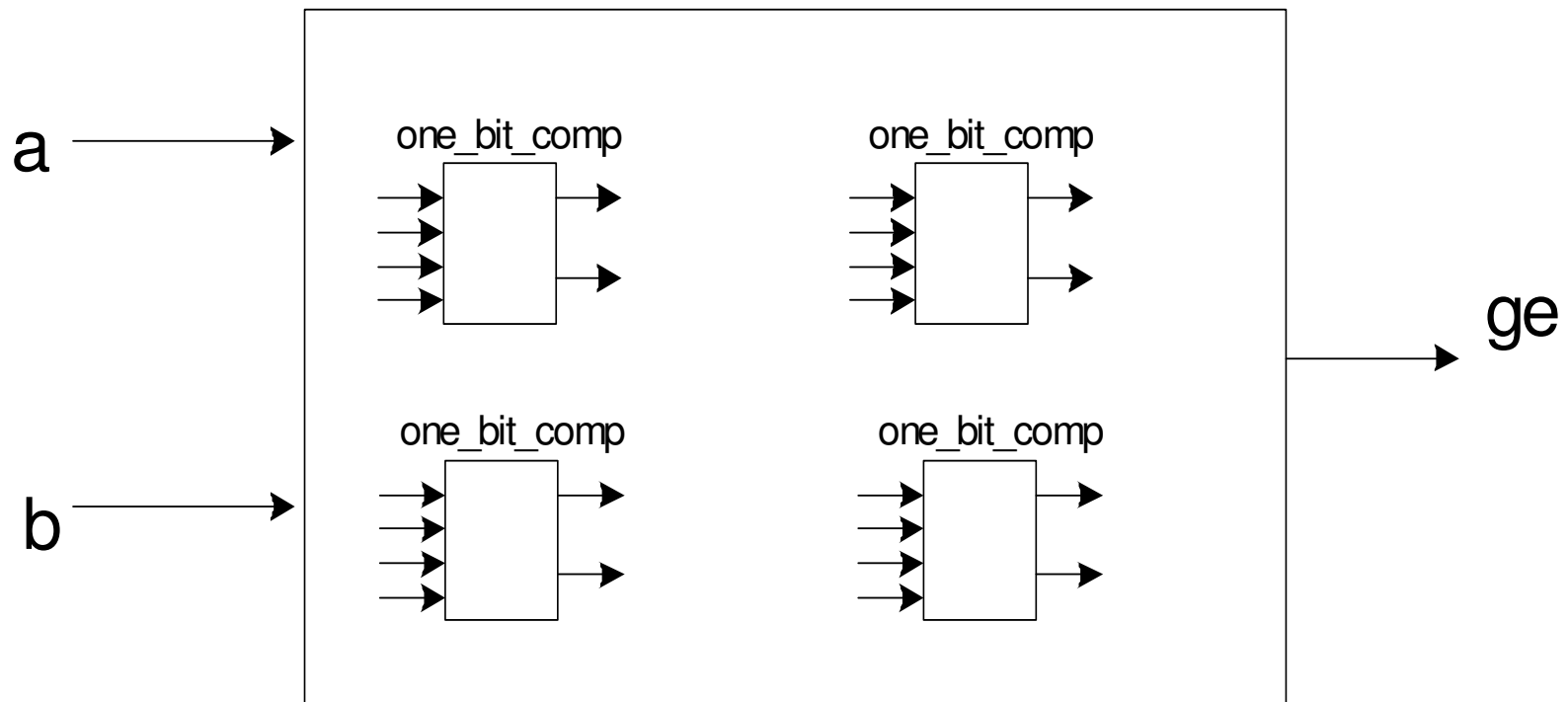


PartI: Bottom Level Testing (2)

- Ideal Testing: Exhaustive Testing
 - Every possible input combination has been tested. Can we do it here?
- Determine the truth table first
- Write a testbench that test every combination of the circuit
- This circuit is 100% tested!

PartI: Intermediate Testing (1)

four_bits_comp





PartI: Intermediate Testing (2)

- Can we do Exhaustive Testing Here?
- Two sets of four bit inputs:
 - $16 * 16 = 256$ possible inputs/ outputs
- Use a for or a while loop to go through all 256 combinations
 - Test benches are the **ONLY PLACE YOU MAY USE FOR LOOPS**



PartI: System Level Testing (1)

```
reg[3:0] ma[1:16]; // Create a memory array
initial begin

    // read the file specified and put the values in 'ma'
    $readmemh("data_vector", ma);
    for(i=1; i<=16; i= i + 1) begin
        // Remember to advance the time forward
        #(`half_cycle * 4)
        in = ma[i];
        $display("in = %d, peak = %d", in, peak);
    end
end
```



PartI: System Level Testing (2)

- Read a test vector from a file
- Make sure you get a good coverage with your test vectors
 - Designing test vectors isn't easy
 - It's a bit of a black art
- Read up on the \$ statements in the Verilog reference (online)



PartII: ChipScope (1)

- Software based logic analyzer
 - Get results on the computer
- Put a logic analyzer right into the FPGA
 - ICON – Connects FPGA to software
 - ILA – Does the actual analysis
- More flexible than the bench analyzers
- But not as timing accurate



PartII: ChipScope (2)

- Steps to use ChipScope
 - Generate an ICON
 - Generate an ILA
 - Connect the ILA to the ICON in your design
 - Synthesize, and implement your design
 - Program the CaLinx board
 - Run the ChipScope Pro Analyzer



PartII: ChipScope (3)

- Similarities/Differences
 - Triggering is just like before
 - Data/Trigger can be MUCH bigger
 - Data is captured synchronously
 - Much easier to view waveforms



PartII: ChipScope (4)

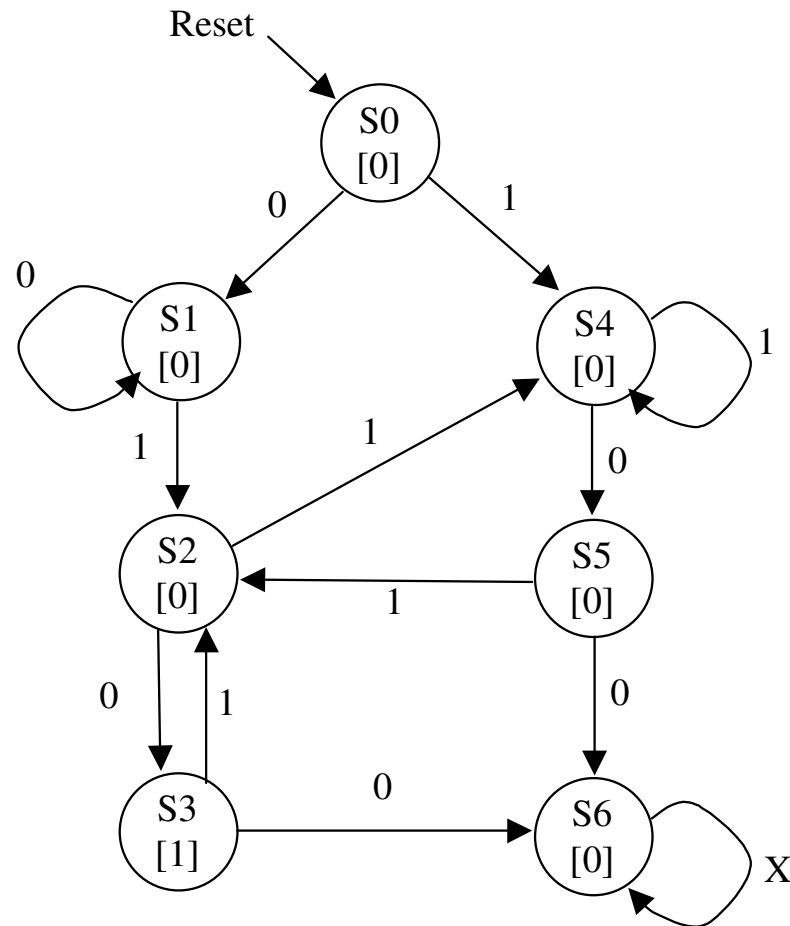
- You will NEED ChipScope
- Plus maybe some additional hardware
 - You're comparing a Counter and a BrokenCounter
 - ChipScope can't do it all for you
 - You'll need some extra hardware
- Detailed ChipScope Tutorial
 - <http://inst.eecs.berkeley.edu/~cs150/Documents.htm>



PartIII: Test FSM (1)

- You must exercise every transition
- Verify every state and output
- You do not need to correct this FSM
 - You just need to draw a correct bubble and arc diagram for your TA
- This is boring, but necessary
 - You will have bugs in your own FSMs

PartIII: Test FSM (2)





Part IV: Probe Internal Signals

- Simulate the circuit to make sure it works properly
- Set probe points on internal signals
- Download to the board
 - Use the bench analyzer
 - Or ChipScope



Part IV: Design Your Solution

- First, find the problem signal
- Second, think the problem out
- Third, design a solution
 - Perhaps consult your TA
 - You will need to really think this out
 - If you try and just build it, it probably wont work quite right
- Fourth, implement your design